



SID4 UHR

ULTRA HIGH RESOLUTION WAVE FRONT SENSOR

SID4 UHR Ultra High Resolution wavefront sensor is adapted for optics metrology needs. It combines the SID4 ease of implementation with high sampling and resolution. Its large aperture allows to get a live wavefront measurement over the complete sample under test. The SID4 UHR is optimized for **surface inspection** (roughness, high frequency defects detection...) and **optical components characterization** (lens, objective, aspherical and freeform optics...).

Built with a high-performance camera it provides incredible precision for laser characterization. The 540×540 phase map sampling with such compactness make the SID4 UHR a unique tool for optics metrology in both research and industry fields.

KEY FEATURES



High Resolution 540 x 540





Instantaneous measure on large Field



High Dynamic range



Optimal signal to noise ratio



Large analysis pupil



Compactness for easy implementation



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WAVE FRONT SENSOR

APPLICATIONS

Optical components characterization

Surfaces inspection

SPECIFICATIONS

Wavelength range	400 - 1100 nm
Aperture dimension	14.9 x 14.9 mm ²
Spatial resolution	27.6 µm
Phase and intensity Sampling	540 x 540
Phase resolution (1)	2 nm RMS
Real-time processing frequency (2)	1 Hz (full resolution)
Interface	USB 3.0
Dimensions (W X H X L)	73 x 71 x 84 mm ³

- (1) At processing frequency of 1 Hz
- (2) Using the computer provided by PHASICS on SID4 Software